A Systematic Study of Correlation between Surface Roughness and Microwave Effective Conductivity of Copper Foils for Ultra-Low-Loss Applications

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MIKON 2024, Wroclaw, 1-4 July 2024

Outline

1. Motivation.
2. Measurements.
3. Results.
4. Conclusions.

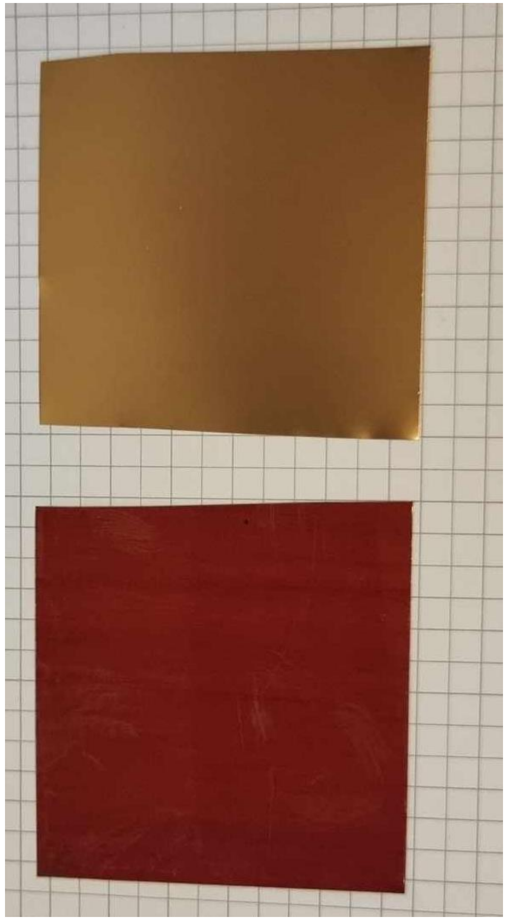
Motivation

- Need for ultra-low-loss materials in high frequency electromagnetic design and techniques allowing precise determination of such materials.
- Developing microwave and millimetre-wave resonators for stand-alone copper foils samples measurements as an alternative for time-consuming and cumbersome tests of circuit manufactured on a PCB.
- Better understanding of the impact of individual processes in the production of copper foils.

Measurements

Samples

- 24 types of copper foils by CFL.
- Each type is different combination of base foil and treatment and also delivered in two thicknesses 35 μm and 70 μm.
- Roughness parameters were measured for each sample by CFL.

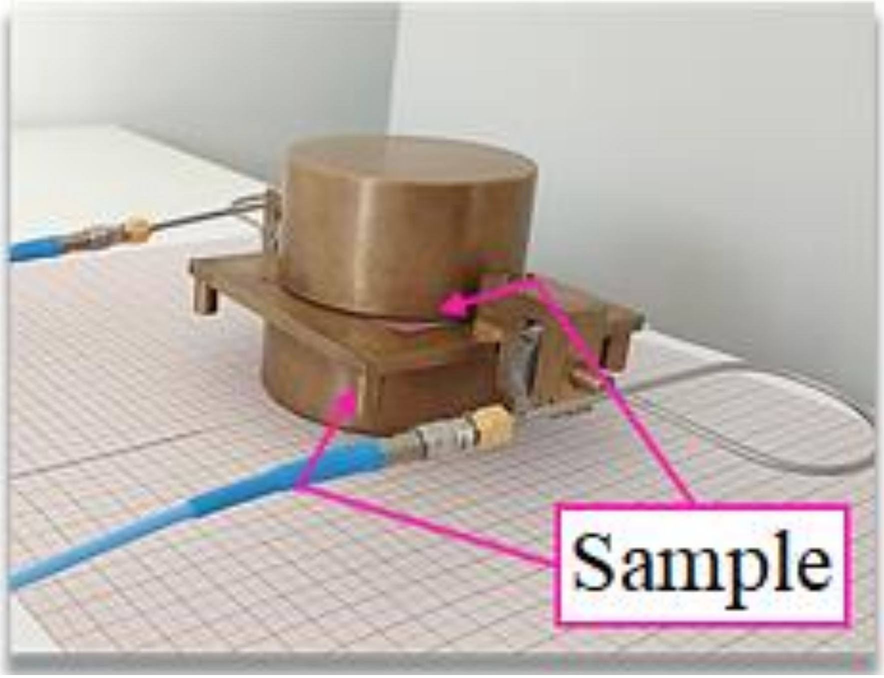


CIRCUIT FOIL

Measurements

Ruby Dielectric Resonator (RuDD)

- Foil loss is measured with RuDD operating at 13 GHz .
- RuDD is connected to VNA (Keysight Streamline P5008B), which extract the 3dB bandwith at the resonance.
- A dedicated application convert this to the Q-factor and then calculates the effective conductivity.

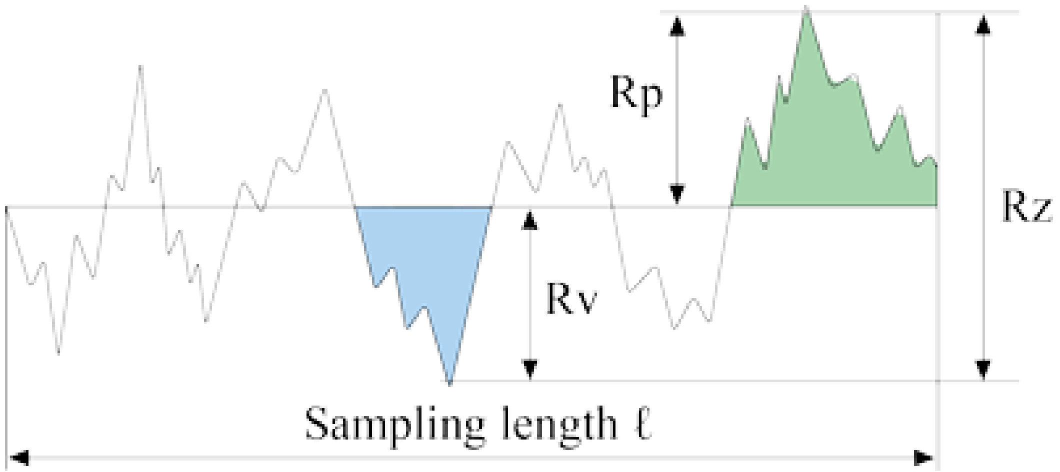


Results

Roughness parameters (contact stylus profilometre)

Maximum Height (Rz)

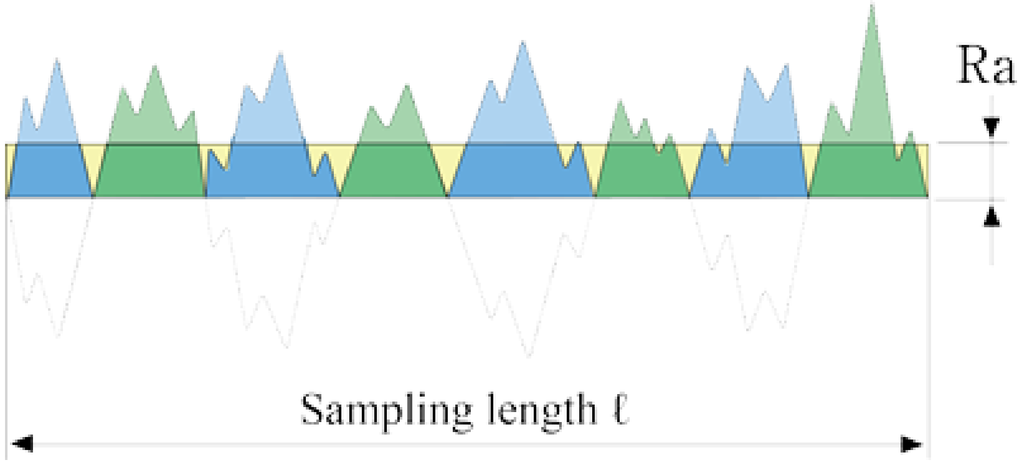
$$Rz = Rp + Rv$$



Olympus*

Arithmetical Mean deviation (Ra)

$$Ra = \frac{1}{\ell} \int_0^{\ell} |Z(x)|\, dx$$



Olympus*

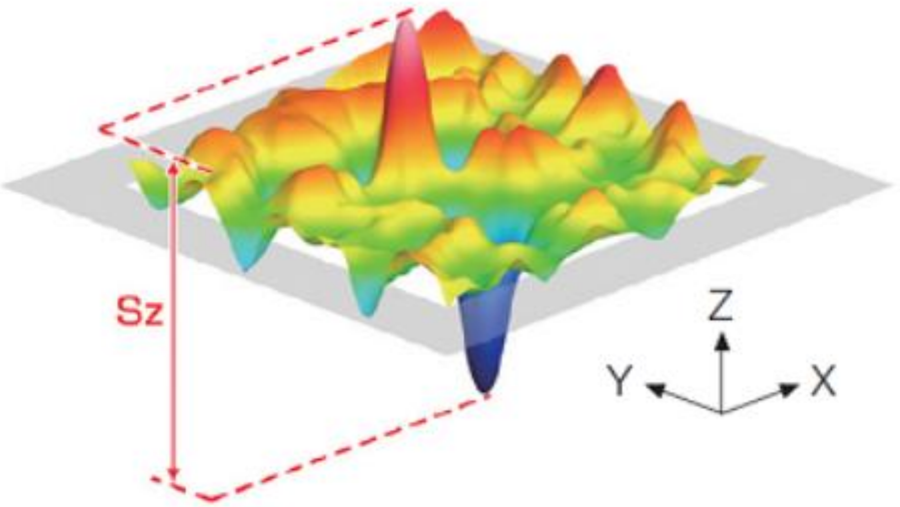
* https://www.olympus-ims.com/en/metrology/surface-roughness-measurement-portal/parameters/#!cms[focus]=cmsContent14708

Results

Roughness parameters (noncontact laser interferometry)

Maximum Height (Sz)

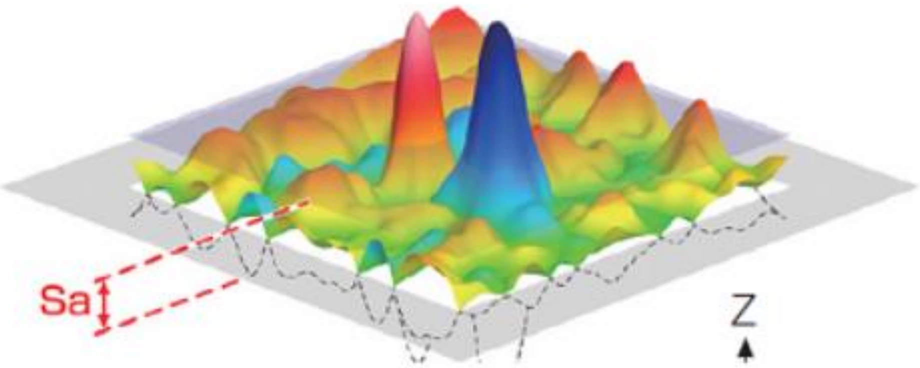
$$Sz = Sp + Sv$$



Olympus*

Arithmetical Mean Height (Sa)

$$Sa = \frac{1}{A} \iint_A |Z(x,y)| \, dxdy$$



Olympus*

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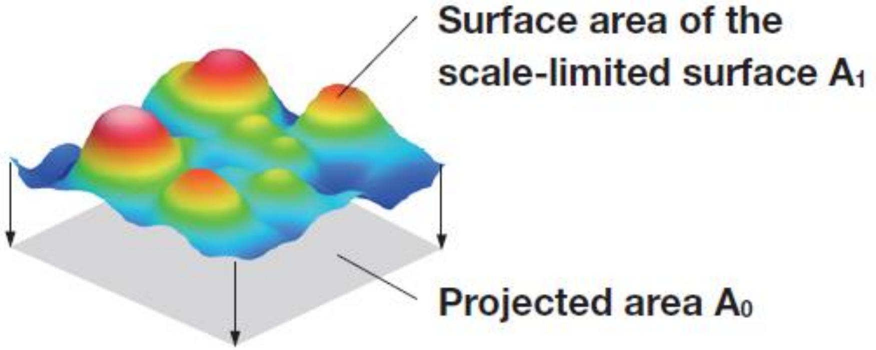
Results

Roughness parameters (noncontact laser interferometry)

Developed interfacial area ratio (Sdr)

$$\mathrm{Sdr} = \frac{1}{A}\left[\iint_A \left(\sqrt{\left[1+\left(\frac{\partial z(x,y)}{\partial x}\right)^2+\left(\frac{\partial z(x,y)}{\partial y}\right)^2\right]}-1\right) dxdy\right]$$



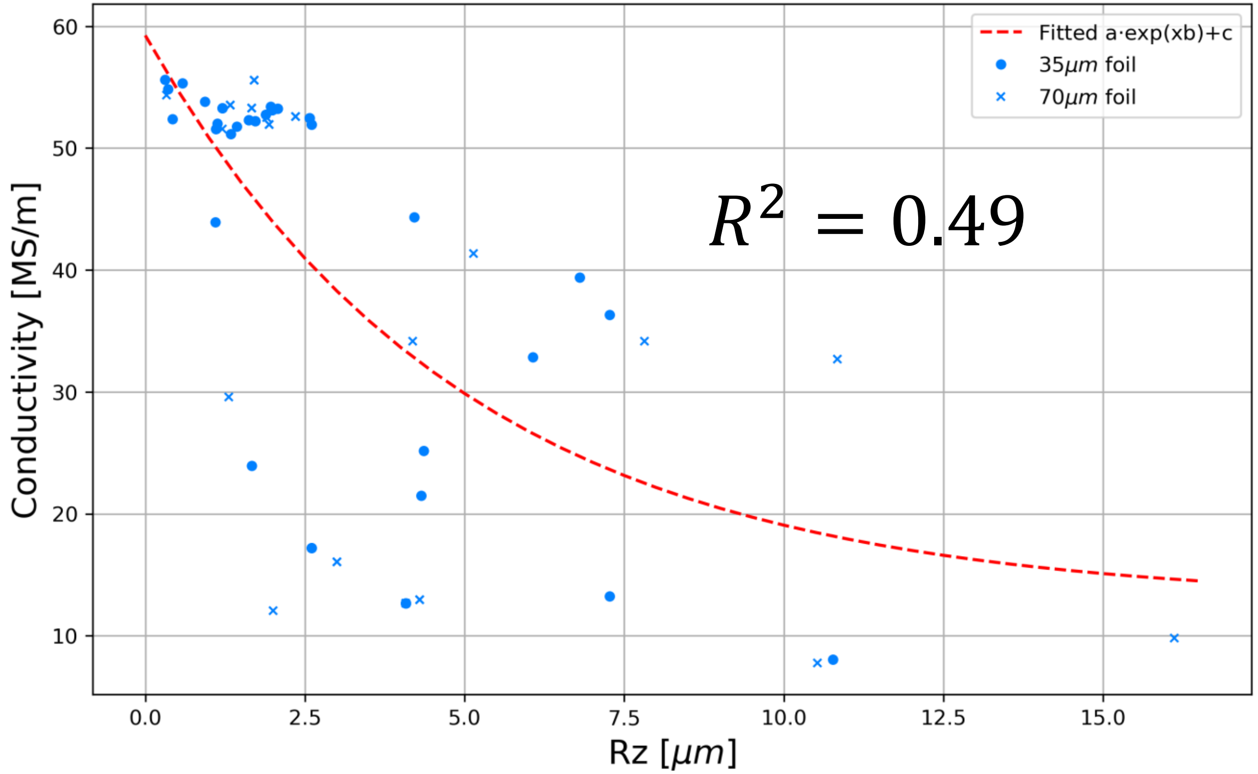
Olympus*

$$\mathrm{Sdr}=\{(A_1/A_0)-1\}\times 100\,(\%)$$

* https://www.olympus-ims.com/en/metrology/surface-roughness-measurement-portal/parameters/#!cms[focus]=cmsContent14708

Results

Correlation Between Effective Conductivity and Surface Roughness



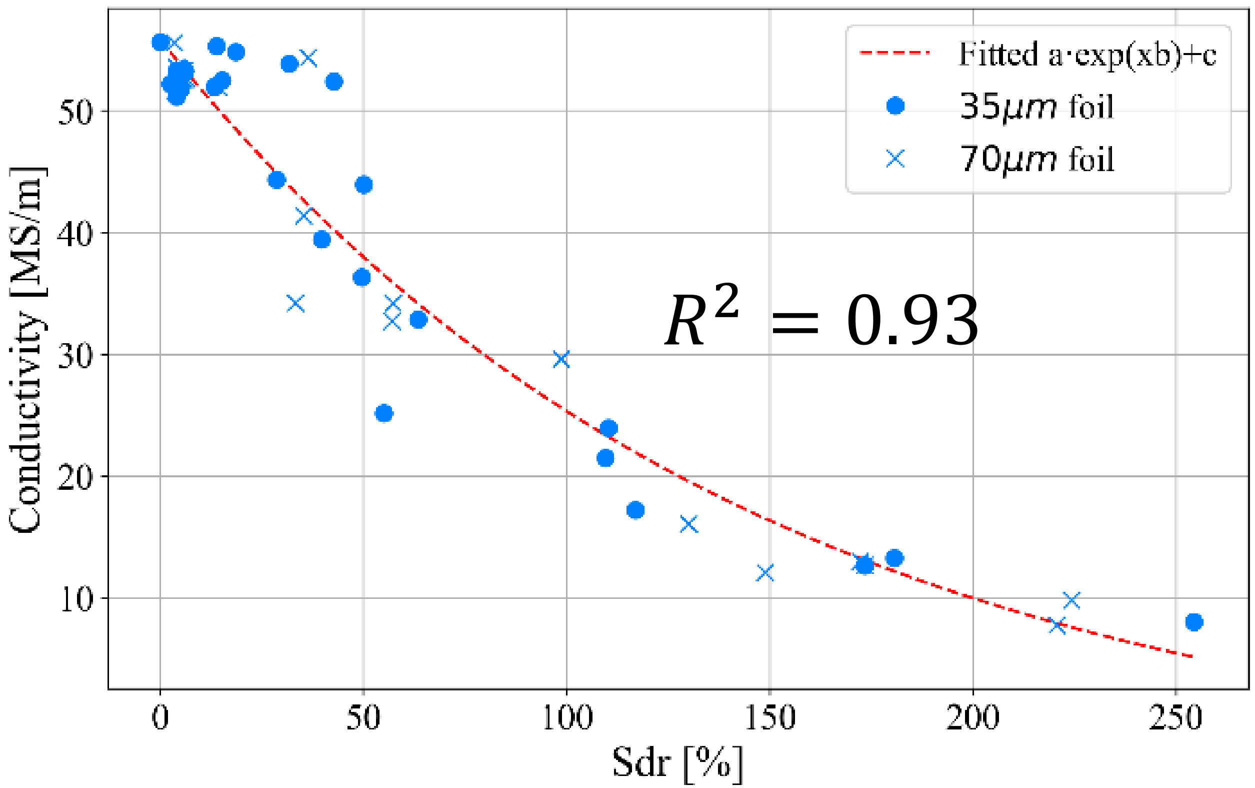
48 measurements (shown here)

Measurement time 2 min per sample (without repeatability study)

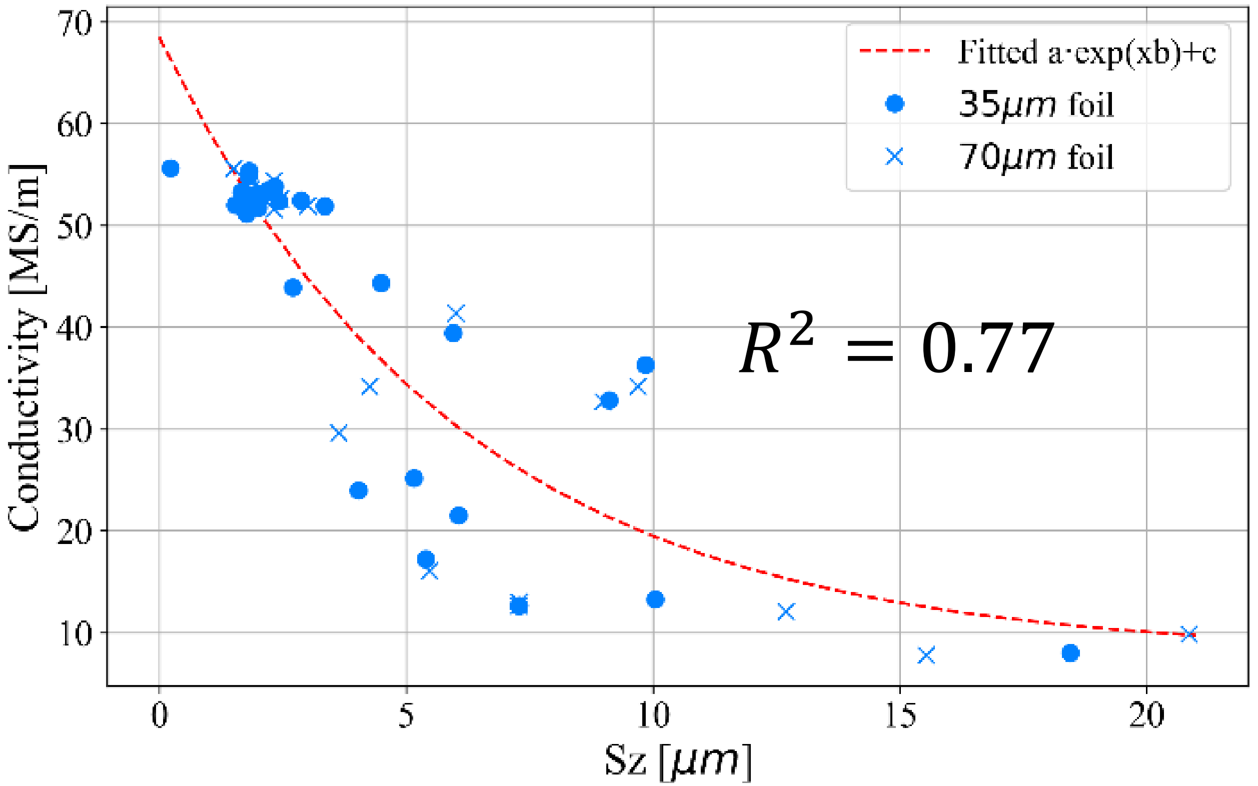
- Effective conductivity decreases (loss increases) with increasing roughness
- But there is no one-to-one realtion between Rz and loss
- Exponential curve: (a=4.65 MS/m, b=−0.2 1/um, c=12.8 MS/m) $R^2 = 0.49$

Results

Correlation Between Effective Conductivity and Surface Roughness



(a=61.4 MS/m, b=-6.87*10^{-3}, c=-5.59 MS/m)



(a=60.7 MS/m, b=-0.16 1/um, c=-7.82 MS/m)

Better fit with noncontact pamateres (than wth Rz on previous slide)
But still not perfect fit.

Conclusions

- We have confirmed that increasing roughness leads to higher loss.
- However we have also shown that roughness-to-loss is not represented by a closed-form fomula.
- Sz or Sdr (from non-contact roughness measurement) give higher correlation to loss, than Rz (from contact measurement).
- It is recommened to measure foils before their aplictaion in mm-Wave circuit design.
- As further expected in view of the electromagnetic considerations, foil thickness is irrelevenat.

Acknowledgment

This work is performed within the EUREKA-Eurostars project 5G_Foil and co-funded by the Polish National Centre for Reaserch and Development under contract DWM/InnovativeSMEs/176/2023 and InnovativeSMEs/4/90/5G_Foil/2023 and by the Luxembourg Ministry of Economy under contract 2023-A127-X187.

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